

Fault Attacks: How Practical are Fault Injection Attacks, Really?

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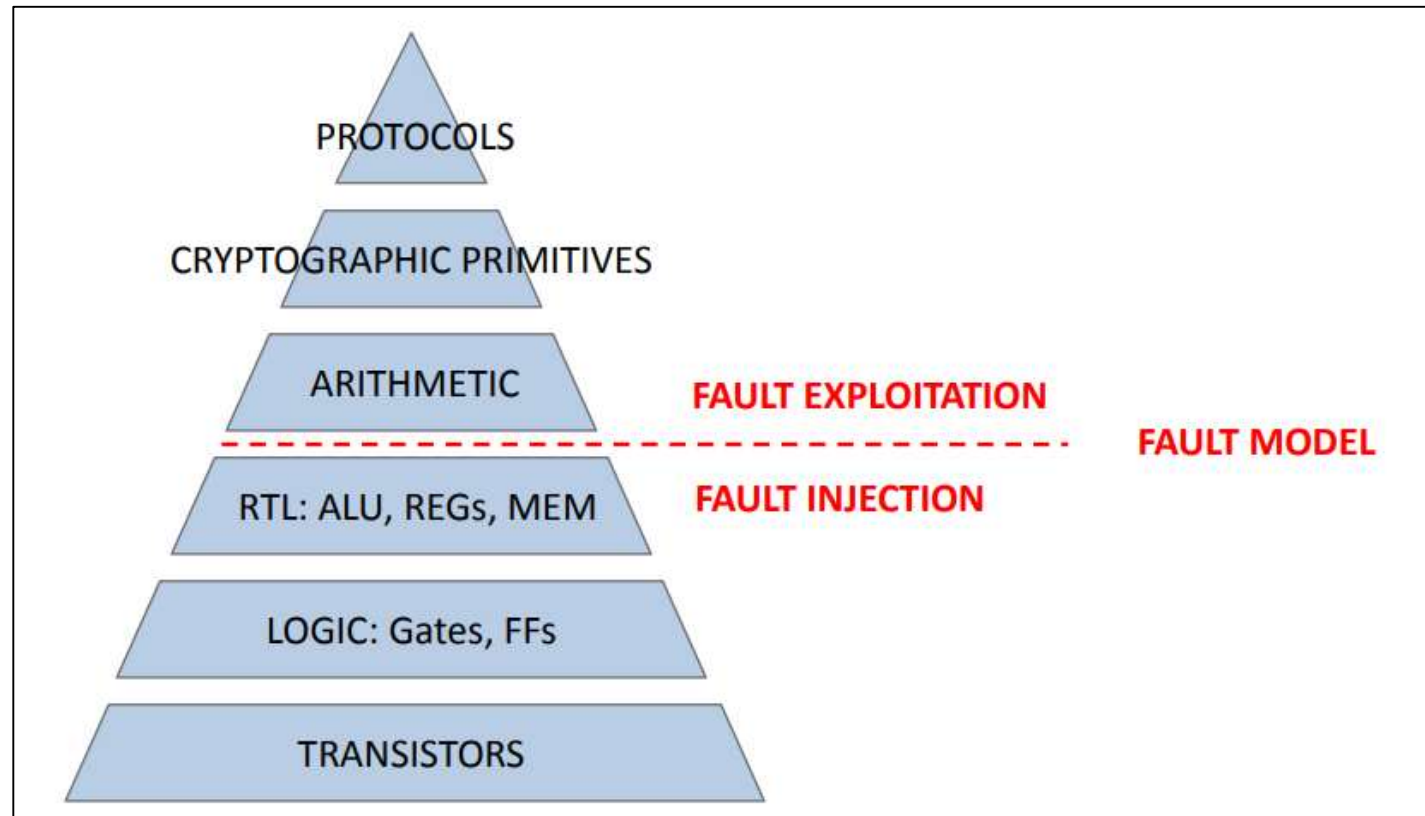
Agenda

- ☐ Introduction
- ☐ Fault Attacks
- ☐ Fault Analysis
- ☐ Fault Countermeasures
- ☐ Case studies
- ☐ Further Resources
- ☐ Conclusions
- ☐ References



Introduction

Introduction



The embedded design space

Introduction

❑ Classification of Attacks

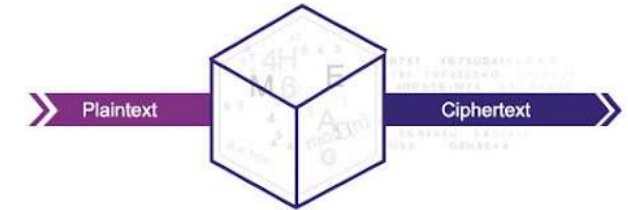
Gray-Box Model

The attacker has access (sometimes physical) to the device.



- A primitive may be secure in black box model but not secure in grey or white box models!
- This talk is about one of the **Grey-box** model.

White-Box Model

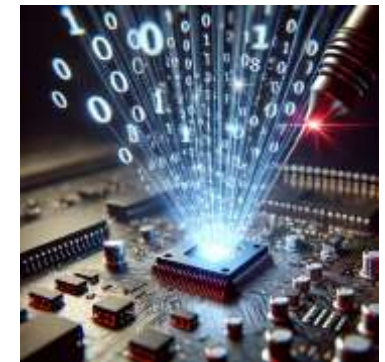


The attacker is inside the system and has access to intermediate values and...!

Black-Box Model



The attacker has access to a set of plaintexts and their corresponding ciphertexts.



Fault Attack

Introduction

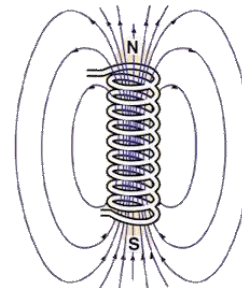
❑ Implementation

Ways to generate a fault [Lomne, 2015]

There are different ways to generate a fault:

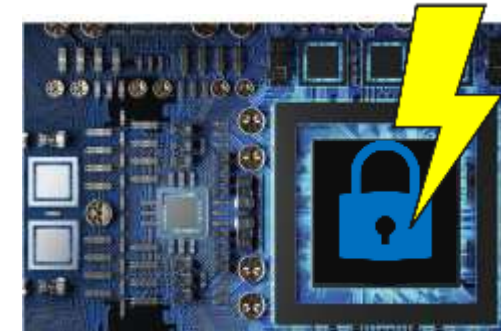
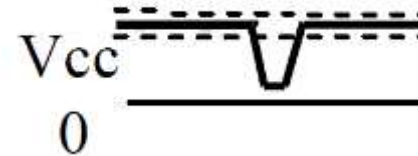
- Electrical glitch on pins (VCC, CLK, I/O,)
- Electrical glitch on the die (FBBI)
- Light injection
- ElectroMagnetic (EM) field injection

Temperature



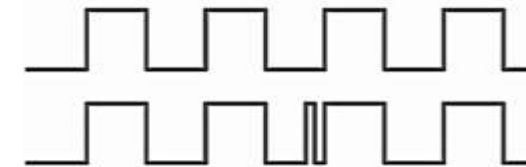
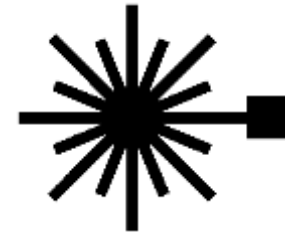
Electromagnetic Pulses

Voltage Spikes



Device Under Attack

Laser Beam



Clock Glitches

Introduction

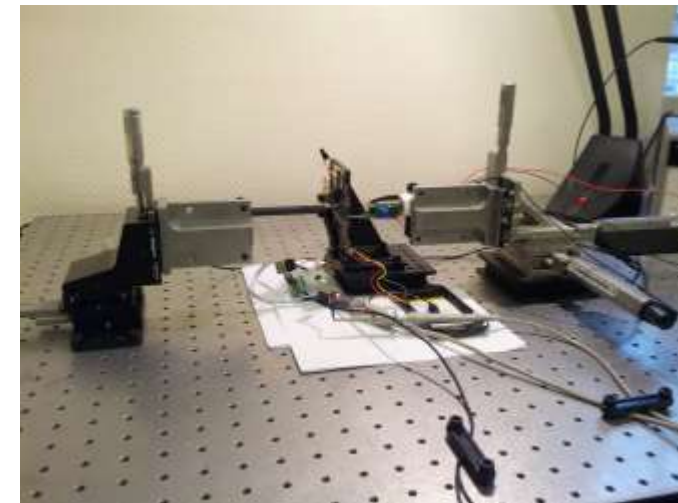
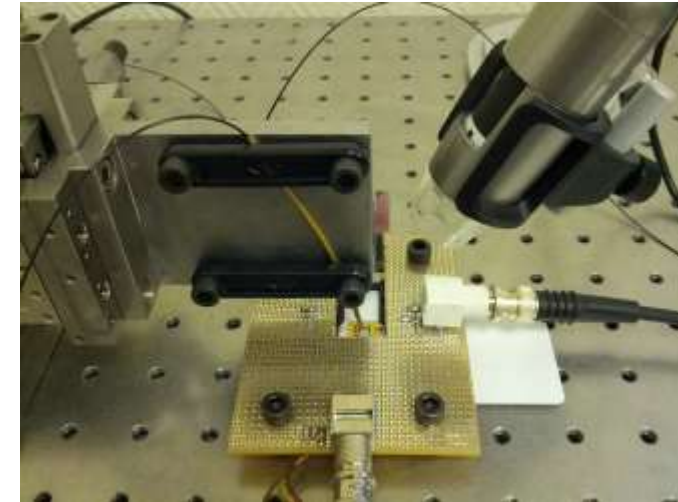
❑ Comparison

Global/Low-Cost/Low-Precision

Clock/Voltage glitch, temperature

Local/High-Cost/High-Precision

Laser, Electromagnetic, Ion Beam



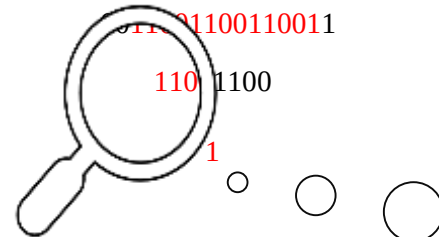
Introduction

❑ Fault Evaluation Route

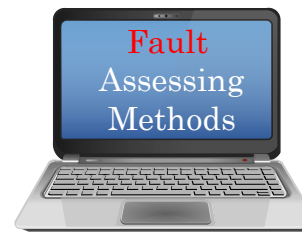
(1) Example:

Faults belong to AES-128 middle Round Intermediate Values

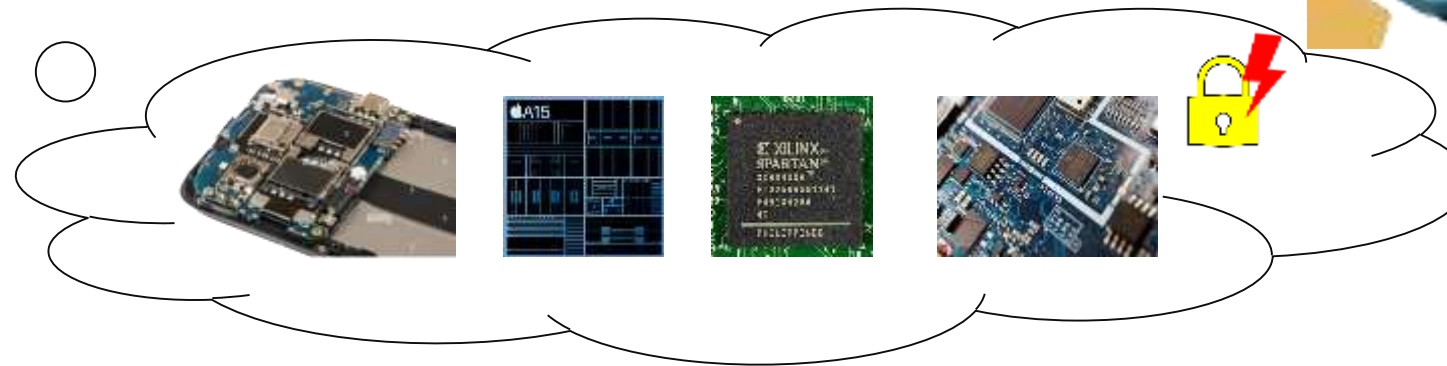
010101.....1011111001111



(2) Analyzing Process



(3) **Recovering** the Master Key or secret values



Introduction

Recent Practical Scenarios in Real World



Voltage Glitch for Recovering Critical Data From Tesla Autopilot [1]



Voltage Glitch on Secure Boot of SpaceX Starlink [2]



EMFI Against Secure Automotive Bootloaders [3]



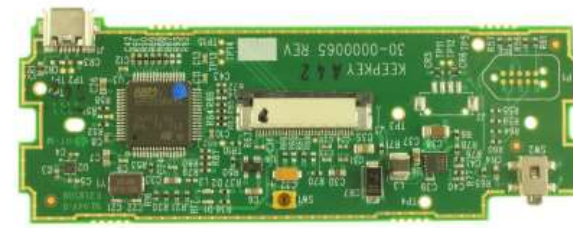
EMFI Against lattice-based signature [4]



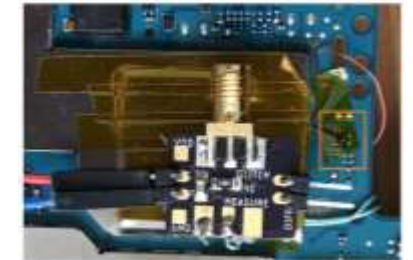
Clock Glitch Against Glitch Detector Structure in 12th Generation Intel Core Processor [5]



EMFI on Apple A4 [6]



Glitching the keepkey hardware wallet [7]



Voltage fault injection on PlayStation Vita [8]

[1]Niclas et al, 2023 [2]Lennert, 2022 [3]Enrico et al, 2023 [4]Prasanna et al, 2019 [5]Amund et al, 2024 [6]Carlton Shepherd et al, 2022 [7]Riscure team, 2022 [8] Yifan Lu, 2019.

Introduction

❑ Why Fault attacks are important?

- **Reveal vulnerabilities** not found in normal testing
- **Real-world consequences:** bypass checks, leak secrets, disrupt safety
- **Low-cost for attackers** yet effective against complex systems
- **Applicable across domains:** smartcards, IoT, automotive, defense



Fault Attacks

❑ Fault attacks categories

- **Non-Invasive:**
No physical modification; e.g., EMFI.
- **Semi-Invasive:**
Limited physical access without full chip removal; e.g., clock/voltage glitching.
- **Invasive:**
Direct modification of the chip with physical access; e.g., laser fault injection after decapsulation.



❑ The focus on this presentation:

- Clock glitching.
- Voltage glitching.
- EMFI.

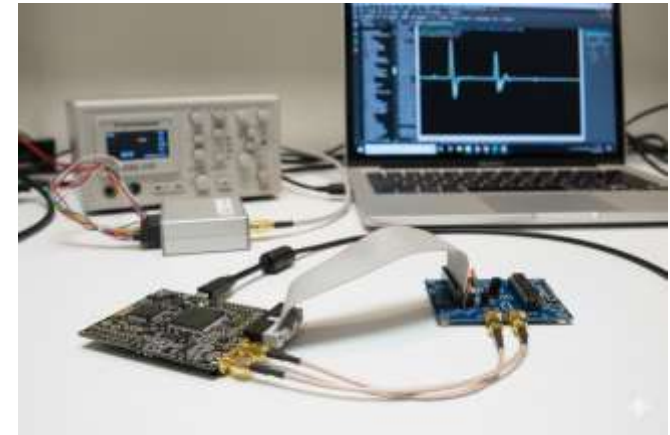
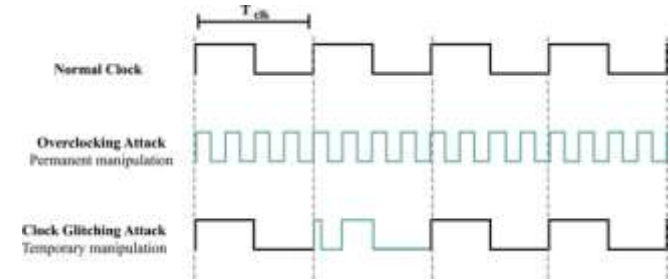


- ❑ Clock Glitching → manipulate the system clock to skip or corrupt instructions.
- ❑ How to perform clock glitching (tools & approaches)

Devices: ChipWhisperer, clock generator, FPGA, oscilloscope & logic analyzer.

Methods: Inject short pulses or jitter on the clock line, replace crystal with controlled source, gate/skip clock cycles with transistor/FPGA.

Monitor: oscilloscope (clock waveform), logic analyzer (trigger timing), UART/LEDs (DUT behavior).

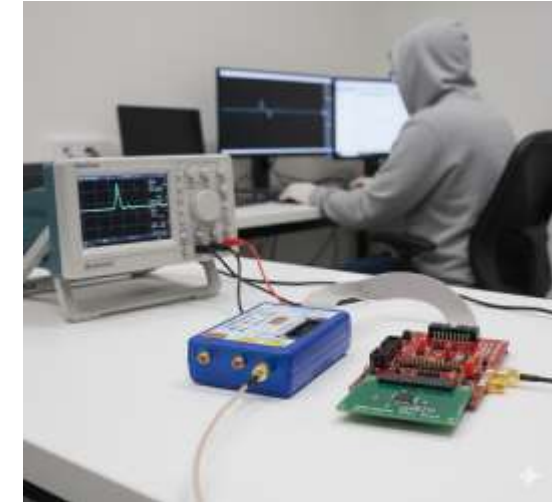
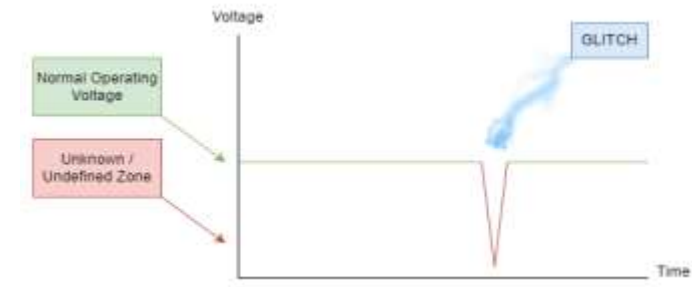


- ❑ Voltage Glitching → inject short voltage drops/spikes to disrupt logic.
- ❑ How to perform voltage glitching (tools & approaches)

Devices: ChipWhisperer, Custom Glitching Hardware, Crowbar circuit.

Methods: Short V_{DD} drop, spikes, capacitor discharge, ground transient injection, crowbar pulses, timed supply gating.

Monitor: High-speed Oscilloscopes.



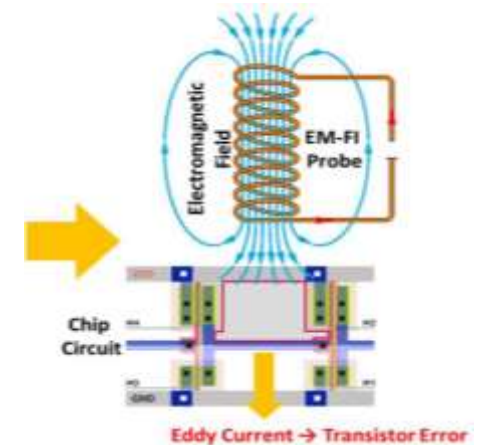
- ❑ Electromagnetic Fault Injection (EMFI) → use EM pulses to induce transient faults in circuits.
- ❑ How to perform EMFI (tools & approaches)

Devices: ChipShouter, EM pulse guns, custom EM coils, high-voltage pulse generators, Langer near-field probes, Riscure EMFI.

Methods: Near-field EM pulses injected into silicon, spatial scanning for sensitive spots, timed pulses during execution.

Positioning: motorized or manual XYZ stages let you do systematic spatial scans.

Monitor: Python scripts to log, timestamp, and classify outputs.



Key parameters in Fault injection attacks [1]

Parameters	Description
Number of Fault Injection Events (n)	The number of physical fault injections performed in a specified time window
Fault Location (l)	Precise: Specific gate(s) Loose: Specific cluster of gates, no/partial control on which gates are affected No control: Random location
Fault Timing (t)	Precise: Specific clock cycle/operation Loose: Set of clock cycles/operations No control: Random timing
Number of Affected Bits (b)	The number of affected bits by the fault injection
Duration of the Injected Fault (d)	Transient: Limited, self-recoverable Persistent: Limited, needs to be explicitly overwritten Destructive: Irreversible
Targeted Gate Type (g)	Combinational gates only Memory gates only Both
Fault Type (p)	Set: Faulting to 1 Reset: Faulting to 0 Random: Random outcome Flip: Flipping the value Custom: Attacker specified gate modification

Fault Analysis

Fault Analysis Methods

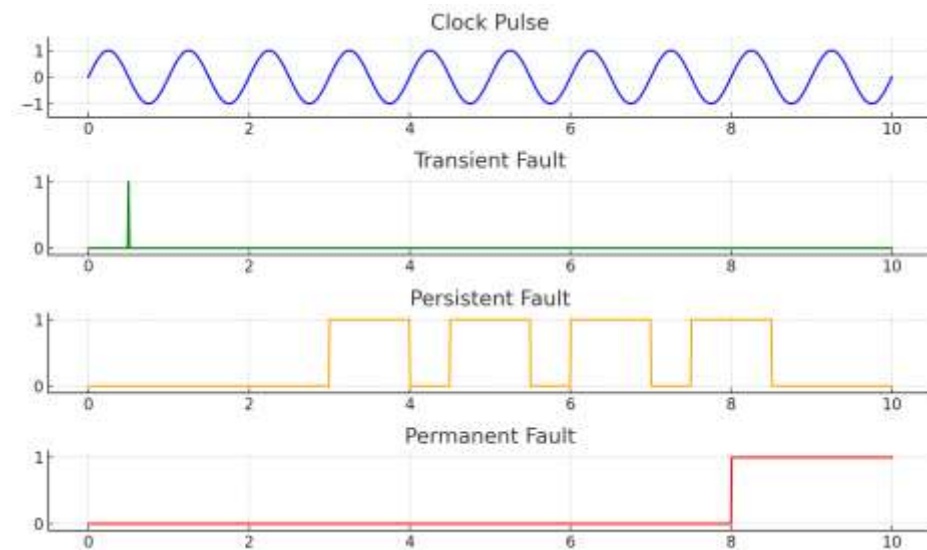
❑ Classifications of Fault model: Duration and impact

➤ How long it will stay:

- Transient Fault: Affect one encryption
- Permanent Fault: Always present
- Persistent Fault: Hybrid model between transient and permanent. Persist over several encryptions but disappears on reboot. Typically targets stored constants (ex. S-box in memory)

➤ What it will affect:

- Modification of operation flow
- Changing a specific bit/ byte/ word or random
- Which round, a specific round or random



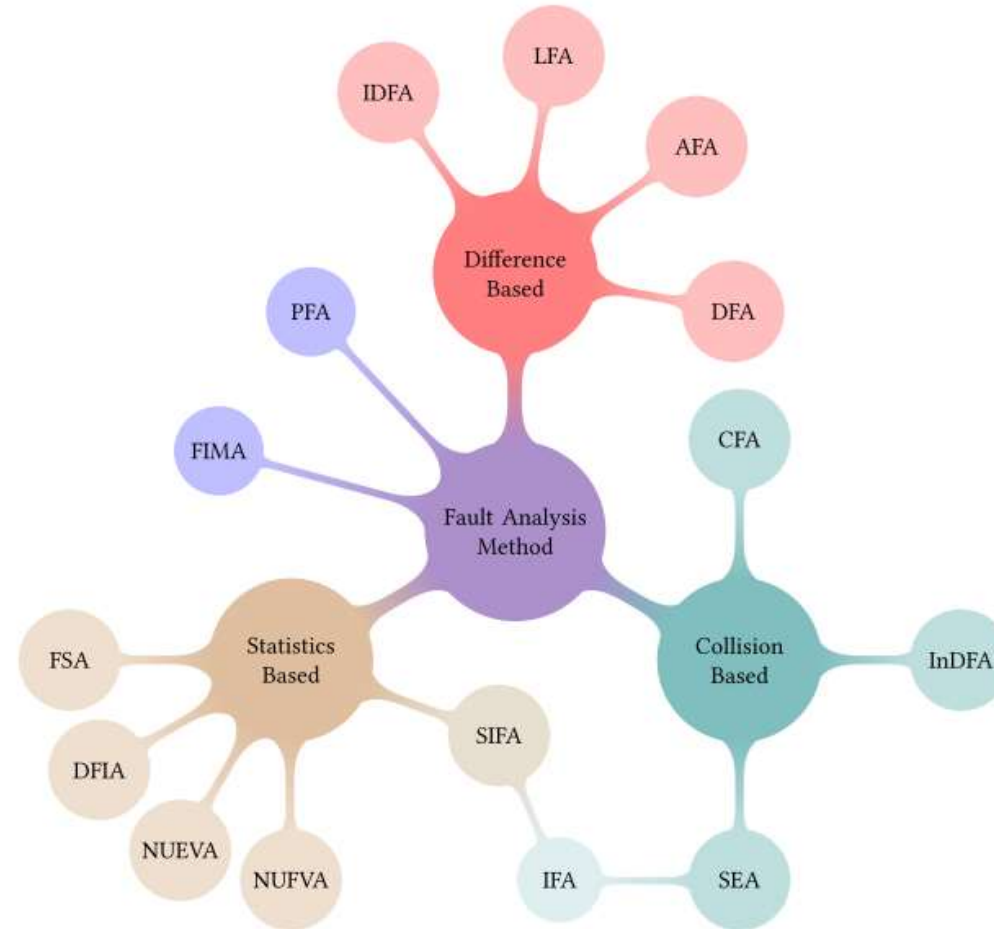
Fault Analysis Methods

□ Cryptanalysis approaches

Different models of FA from Cryptanalysis point of view

- Differential fault analysis (DFA)
- Statistical fault analysis (SFA, SIFA, SEFA, ...)
- Persistent fault analysis (PFA, MPFA, SIPFA)
- ...

Fault Analysis Methods



Classification of fault analysis methods. [2]

Fault Countermeasures

Fault Countermeasures

➤ Redundancy based implementation

- Detection
- Correction
- Infection
- Cipher-based

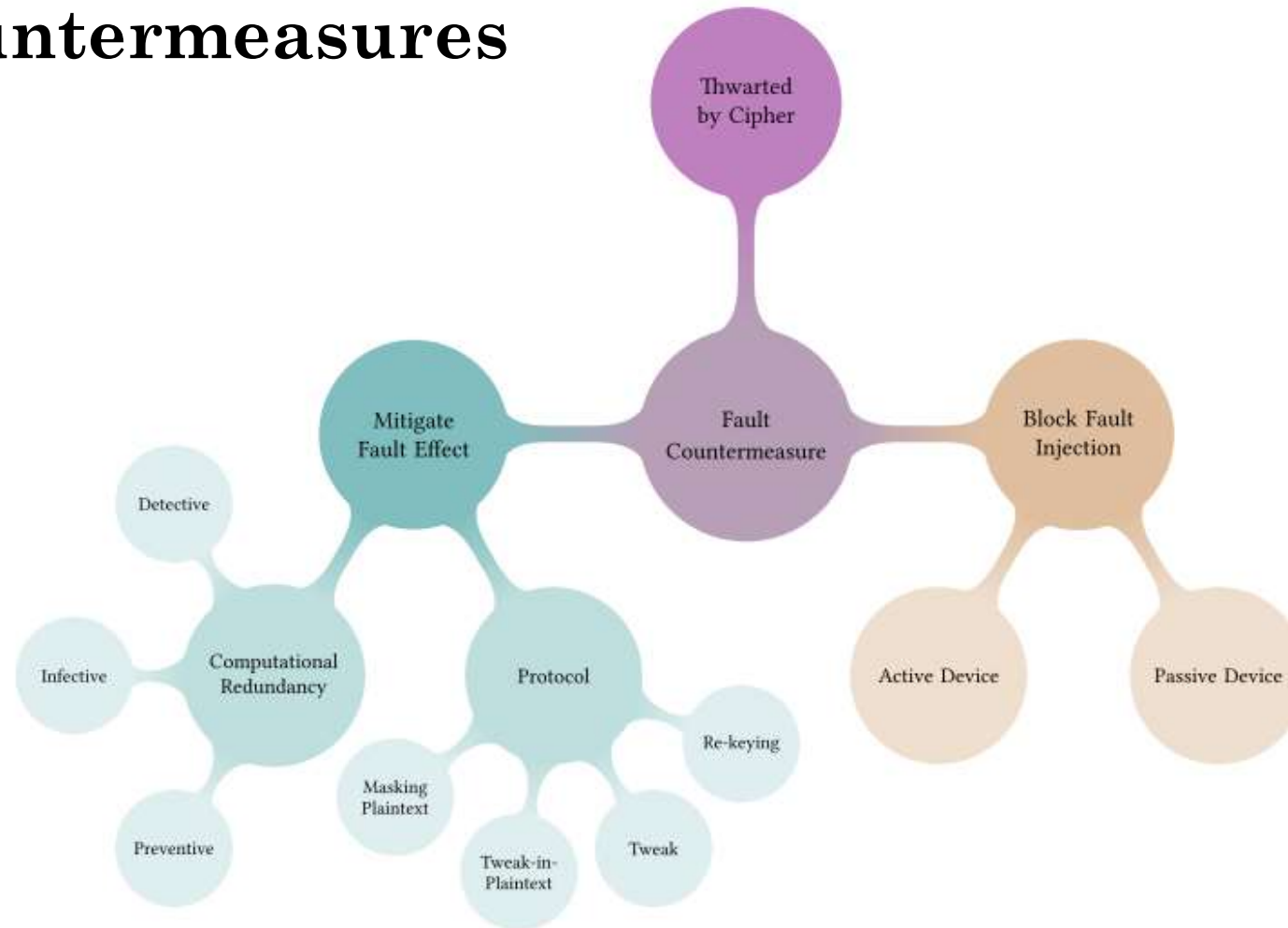
➤ Physical Circuit

- Shield
- Physical Detector
- Tamper Detector
- Package

➤ Protocol

- Re-keying
- Masking plaintext
- Tweak
- Padding

Fault Countermeasures



Generic overview of [fault attack countermeasures](#). [2]

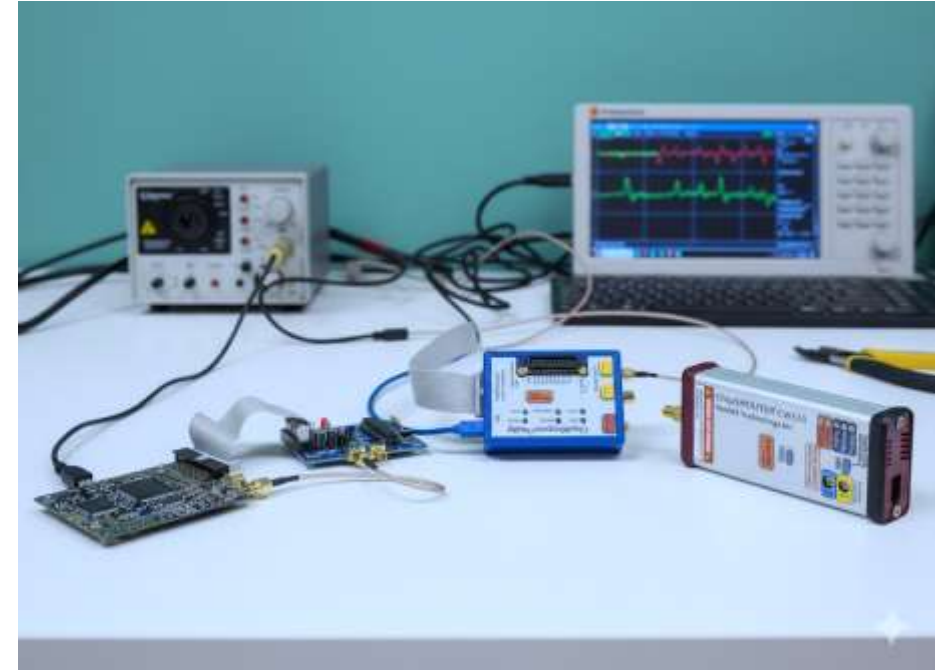
Case studies

❑ NewAE experimental setup:

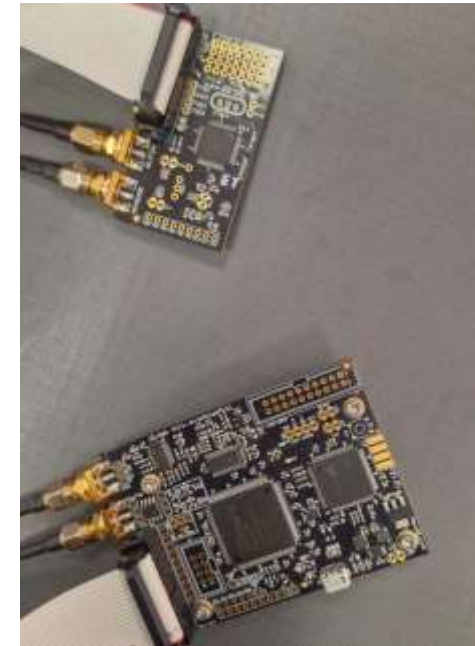
- Chipshouter
- Chipwhisperer lite
- Chipwhisperer Husky
- CW305 Target board

❑ Our attack scenarios:

- Using Chipwhisperer lite to make Voltage glitch on STM32 target.
- Using Chipwhisperer Husky to make Clock glitch on cw305 Target board.
- Using Chipshouter with its original Target



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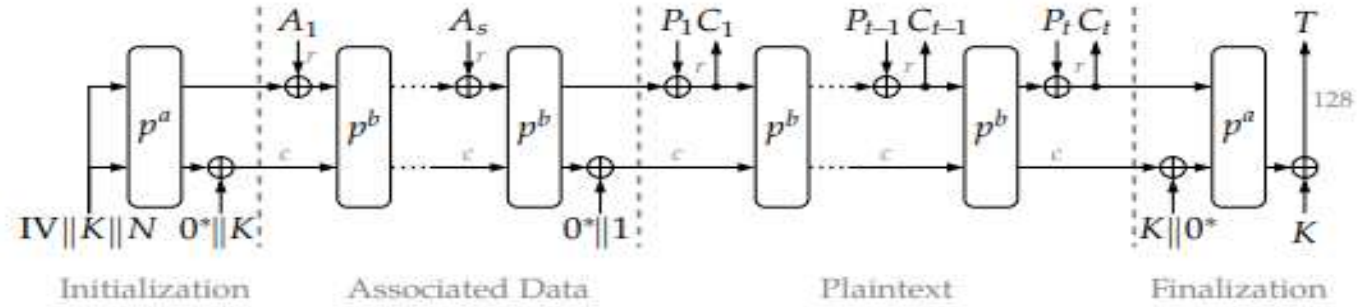
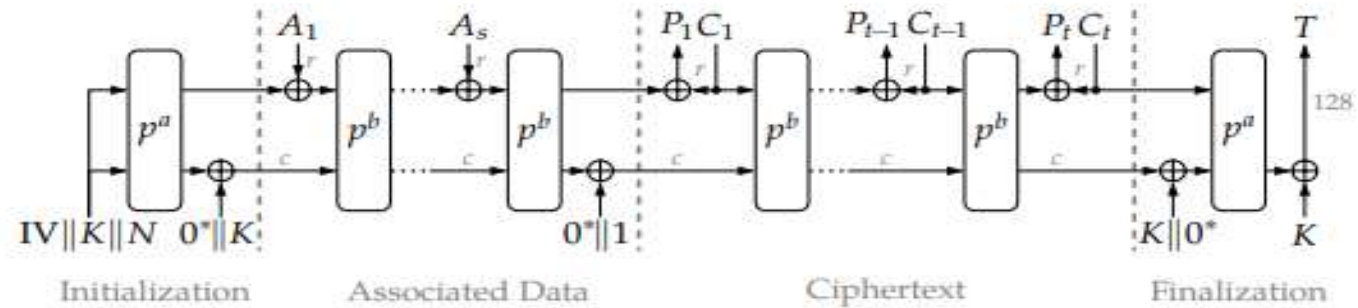
- Chipshouter
- Artix7 Xilinx board.
- STM32f405 development board.

❑ Our attack scenarios:

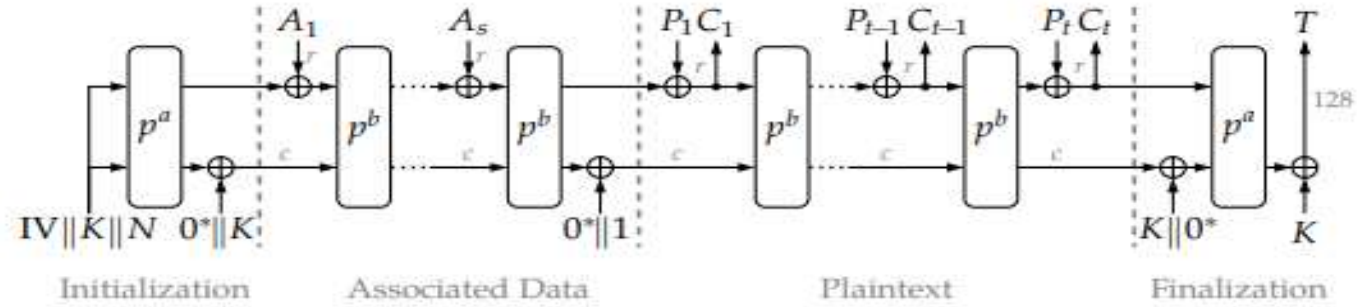
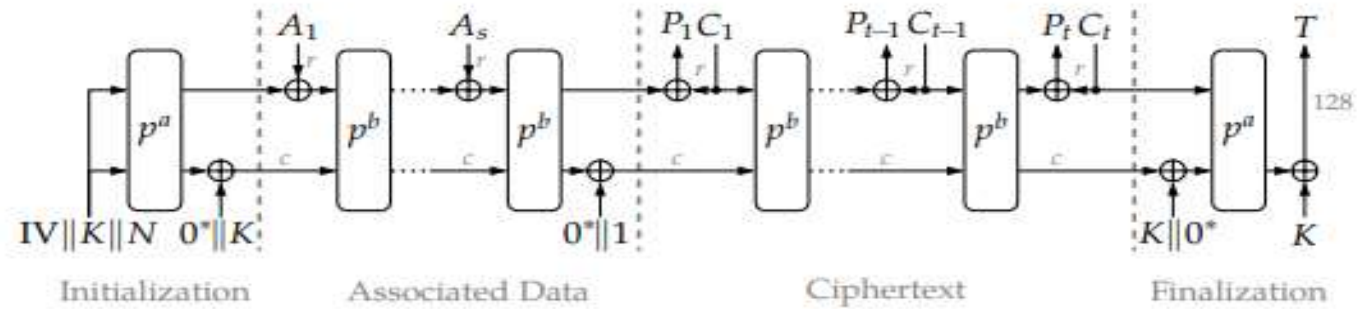
- Using Chipshouter to make ASCON algorithm output faulty on:
 1. Artix7 FPGA
 2. STM32f405 ARM

- ❑ Using Chipshouter to make ASCON algorithm output faulty on ARTIX7.



(a) Encryption $\mathcal{E}_{k,r,a,b}$ (b) Decryption $\mathcal{D}_{k,r,a,b}$

Name	Algorithm	Bit size of				Rounds	
		key	nonce	tag	data block	p^a	p^b
ASCON-128	ASCON _{12,6} -128-64	128	128	128	64	12	6

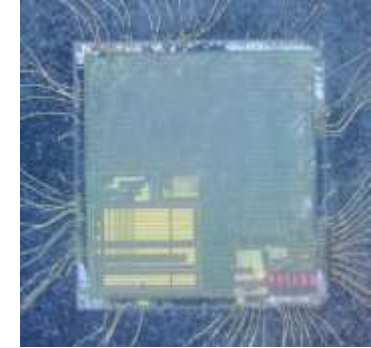
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- ❑ Using Chipshouter to make ASCON algorithm output faulty on ARTIX7.



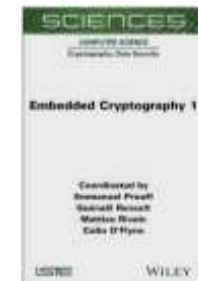
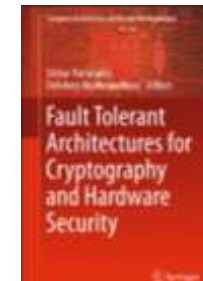
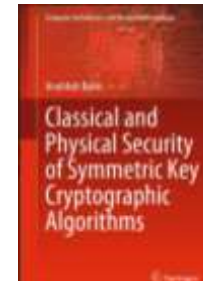
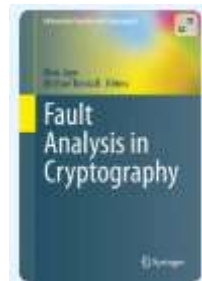
- ❑ Using Chipshouter to make ASCON algorithm output faulty on STM32F405.



Further Resources

□ Useful Books:

- **The Hardware Hacking Handbook: Breaking Embedded Security with Hardware Attacks**, by Colin O'Flynn and Jasper van Woudenberg.
- **Fault Analysis in Cryptography**, by Michael Tunstall, Marc Joye.
- **Hardware Security Training, Hands-on!** by Farimah Farahmandi, Mark Tehranipoor, and N. Nalla Anandakumar.
- **Hardware Security Primitives**, by Mark Tehranipoor , Nitin Pundir , Nidish Vashistha , Farimah Farahmandi.
- **Introduction to Hardware Security and Trust**, by Mark Tehranipoor
- **Classical and Physical Security of Symmetric Key Cryptographic Algorithms**, by Anubhab Baksı.
- **Fault Tolerant Architectures for Cryptography and Hardware Security**, by Sikhar Patranabis, Debdeep Mukhopadhyay
- **Embedded Cryptography 1**, Emmanuel Prouff, Guénaél Renault, Mattieu Rivain, and Colin O'Flynn.



❑ Major Academic Platforms:

➤ Where to Publish: top journals and conferences

- IACR Transactions on Cryptographic Hardware and Embedded Systems (TCHES)
- Journal of Cryptographic Engineering (Springer).
- Journal of Hardware and Systems Security (Springer).
- IEEE Transactions on Information Forensics and Security (TIFS).
- IEEE Transactions on Dependable and Secure Computing (TDSC).
- IEEE Transactions on Computer-Aided Design of Integrated Circuits and Systems (TCAD).
- CHES — Cryptographic Hardware and Embedded Systems (IACR).
- IEEE HOST — Hardware Oriented Security and Trust.
- COSADE — Constructive Side-Channel Analysis and Secure Design.
- FDTC — Fault Diagnosis and Tolerance in Cryptography.
- CARDIS — Smart Card Research & Advanced Applications.
- DATE — Design, Automation & Test in Europe.
- DAC — Design Automation Conference.

➤ Who's leading the research: Top labs around world

- IAIK, Graz University of Technology, Austria.
- The Labs of "EnICS Labs", Israel.
- Ruhr-Universität Bochum, Germany.
- Cryptographic Engineering Research Group (CERG), George Mason University, USA.
- Hardware & Embedded Systems Lab (HESL), Nanyang Technological University of Singapore.
- Computer Security and Cryptography Group, ETH Zurich
- Hardware Security and Cryptographic Processor Lab, Tsinghua University, Beijing, China
- Keysight Technologies Netherlands Riscure BV.
- Secure-IC, France.
- Fraunhofer Institute for Applied and Integrated Security.

❑ Conclusion

- Fault injection reveals **hardware vulnerabilities** missed by normal testing.
- Fault analysis methods help make meaningful sense of complex faulty outputs.
- After identifying weaknesses, applying suitable fault countermeasures is the best way to strengthen the system.
- Practical fault injection via Clock glitch, voltage glitch, and EMFI.
- Practical tools like **Chipshouter** and **Chipwhisperer** make these attack accessible for research.

• Key Inspired References

- [1] Dilara Toprakhisar , Svetla Nikova , and Ventzislav Nikov, “SoK: Parameterization of Fault Adversary Models Connecting Theory and Practice”, Springer Nature Switzerland AG 2024 E. Oswald (Ed.): CT-RSA 2024, LNCS 14643, pp. 433–459, 2024.
- [2] Anubhab Baksi and Shivam Bhasin, et al., “A Survey on Fault Attacks on Symmetric Key Cryptosystems”, *ACM Computing Surveys*, Vol. 55, No. 4, Article 86. Publication date: November 2022.
- [3] Niclas Kuhnappel, Robert Bühren. et al., “EM-Fault It Yourself: Building a Replicable EMFI Setup for Desktop and Server Hardware”, *IEEE Physical Assurance and Inspection of Electronics (PAINE)*. 2022.
- [4] Aghaie, A., Moradi, A., et al., “Impeccable circuits”, *IEEE Trans. Comput.* 69(3), 361–376 (2020).
- [5] Carlton Shepherd, Konstantinos Markantonakis, et al., “Physical Fault Injection and Side-Channel Attacks on Mobile Devices: A Comprehensive Analysis”, arXiv:2105.04454v6 [cs.CR] 22 Mar 2022.
- [6] Jean-Max Dutertrea, Alexandre Menua, et al., “Experimental Analysis of the Electromagnetic Instruction Skip Fault Model and Consequences for Software Countermeasures”.
- [7] Colin O’Flynn, “EMFI for Safety-Critical Testing of Automotive Systems”.
- [8] Hao Guo, Sayandeep Saha, et al., “Vulnerability Assessment of Ciphers To Fault Attacks Using Reinforcement Learning”.

Any questions?



Thank you!

